

**PATENT NUMBER and  
ISSUE DATE**

**U.S. UTILITY Patent Application**

APPL NUM 10002000	FILING DATE 12/05/2001	CLASS 352	SUBCLASS 350	GALN CPT	EXAMINER BARTH
----------------------	---------------------------	--------------	-----------------	-------------	-------------------

\*\*APPLICANTS: Chen Kai; Omura Fumihiko; Minamitsu Akihito; Nakamura Shizuo;

**BEST AVAILABLE COPY**

\*\*CONTINUING DATA VERIFIED:

\*\* FOREIGN APPLICATIONS VERIFIED:

JAPAN 2000-372456 12/07/2000

PG-PUB	DO NOT PUBLISH <input type="checkbox"/>	RESCIND <input type="checkbox"/>	
Foreign priority claimed 35 USC 119 conditions met Verified and Acknowledged Examiner's initials		<input type="checkbox"/> yes <input type="checkbox"/> no <input type="checkbox"/> yes <input type="checkbox"/> no	ATTORNEY DOCKET NO 011593
TITLE : Axis determination apparatus, film-thickness measurement apparatus, deposition apparatus, axis determination method, and film-thickness measurement method			

U.S. DEPT. OF COMM./PAT. & TM-PTO-436 (Rev. 12-93)

<b>NOTICE OF ALLOWANCE MAILED</b>		<b>CLAIMS ALLOWED</b>	
<b>ISSUE FEE</b>		<b>DRAWING</b>	
Amount Due	Date Paid	Sheets Drwg.	Figs.Drwg.
<b>TERMINAL</b>			
<b>DISCLAIMER</b>			
<b>PREPARED FOR ISSUE</b>		<b>Application Examiner</b>	
<b>WARNING:</b> The information disclosed herein may be restricted. Unauthorized disclosure may be prohibited by the United States Code Title 35, Sections 122, 181 and 368. Possession outside the U.S. Patent & Trademark Office is restricted to authorized employees and contractors only.			

FILED WITH:

DISK (CRF)

CD-ROM

(Attached in pocket on right inside flap)